

<b>Notice of References Cited</b>		Application/Control No. 10/596,966	Applicant(s)/Patent Under Reexamination SATO, HIDEO	
		Examiner QUANG PHAM	Art Unit 2612	Page 1 of 2

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,189,712 A	02-1980	Lemelson, Jerome H.	340/5.62
*	B	US-4,993,068 A	02-1991	Piosenka et al.	713/186
*	C	US-6,111,506 A	08-2000	Yap et al.	340/572.1
*	D	US-6,137,834 A	10-2000	Wine et al.	375/240
*	E	US-2002/0150282 A1	10-2002	Kinsella, David J.	382/124
*	F	US-6,476,715 B1	11-2002	Bromer, Nick	340/468
*	G	US-2002/0184641 A1	12-2002	Johnson et al.	725/105
*	H	US-2003/0037264 A1	02-2003	Ezaki et al.	713/202
*	I	US-6,672,512 B2	01-2004	Bridgelall, Raj	235/462.46
*	J	US-2004/0022421 A1	02-2004	Endoh et al.	382/115
*	K	US-6,695,207 B1	02-2004	Norris, Jr., Carroll Boyd	235/382
*	L	US-2004/0059925 A1	03-2004	Benhammou et al.	713/189
*	M	US-2004/0108377 A1	06-2004	Rietveld, Robert Victor	235/380

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No. 10/596,966	Applicant(s)/Patent Under Reexamination SATO, HIDEO	
		Examiner QUANG PHAM	Art Unit 2612	Page 2 of 2

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0120556 A1	06-2004	Kono et al.	382/124
*	B	US-2004/0162988 A1	08-2004	Harper, Jack	713/186
*	C	US-2004/0179588 A1	09-2004	Kuffner et al.	375/224
*	D	US-2004/0208632 A1	10-2004	Dietz et al.	398/182
*	E	US-6,813,010 B2	11-2004	Kono et al.	356/71
*	F	US- H,002,120 H	07-2005	Cudlitz, Stephen	235/382
*	G	US-2005/0148876 A1	07-2005	Endoh et al.	600/454
*	H	US-2008/0258864 A1	10-2008	Hattori et al.	340/5.8
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.